

Atom Probe Tomography Standards Workshop

organized by the

*Microscopy Society of America Atom Probe Focused Interest Group (MSA AP FIG)
and the National Institute of Standards and Technology (NIST)*

Wednesday, Nov 12th, 2014 between 1 and 5 p.m.

At NIST Gaithersburg, MD, USA

(One day prior to APT focus topic symposium at the AVS 61 meeting, Baltimore, MD)

With increasing popularity of Atom Probe Tomography (APT) analysis for materials ranging from metals and alloys, to semiconductors, dielectrics, composites, biological and geological materials, there is an increasing need for developing unified global standards for APT experimentation and analysis. The MSA AP FIG along with the NIST is jointly organizing this APT standards workshop to initiate detailed discussions for unifying efforts of APT researchers from universities, national laboratories and industry directed towards development of ASTM/ISO standards for APT analysis. The objective is to identify working groups in order to initiate standards development and research activities. We will discuss the current status and future direction of standards development, ASTM standards and development process, ISO standards, NIST's role in standards development, standardization of data analysis, and standardization of sample preparation and experimentation. We will conclude with a tour of the NIST Gaithersburg facility and gathering for a self-paid dinner at a local restaurant.

Confirmed Speakers

Don Baer (PNNL), David Dierks (Colorado School of Mines), Mark Engelhard, (PNNL), Dieter Isheim (Northwestern University), Krishna Rajan (Iowa State University), Eric Steel, (NIST), Robert Ulfing (CAMECA).

Organizers

MSA AP FIG: Arun Devaraj (PNNL), R. Prakash Kolli (University of Maryland/NIST), Rich Martens (University of Alabama), NIST: Eric Steel (NIST)



Please RSVP to Eric Steel at eric.steel@nist.gov no later than Friday, October 31, 2014 with your full name and country of citizenship. You must be pre-registered to attend the workshop.